

4D Technology

4D TECHNOLOGY
Optical Metrology for a Dynamic World



**Growing a NASA
Sponsored Metrology Project to
Serve Many Applications and
Industries**

**James Millerd
President, 4D Technology**

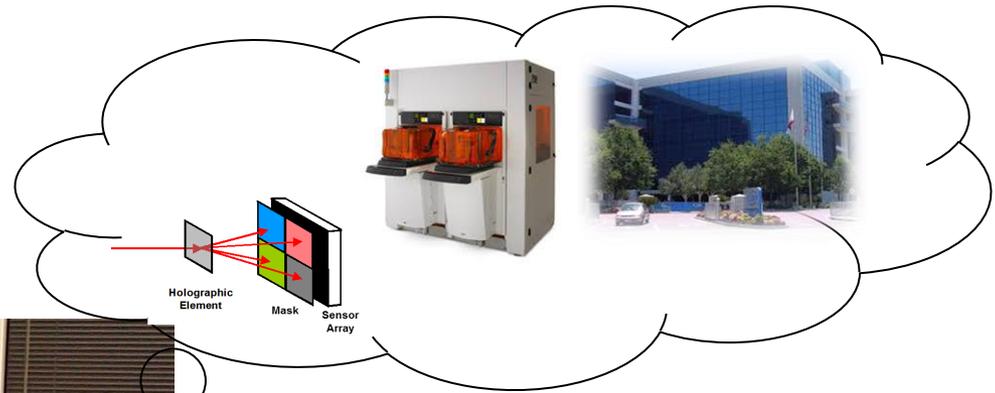


Outline

- ▶ In the Beginning...
 - ▶ Early Technology
- ▶ The NASA Connection
 - ▶ NASA Programs
 - ▶ First success at NASA
 - ▶ Technology Evolution
- ▶ Where We Are Today...
 - ▶ New Applications and Industries



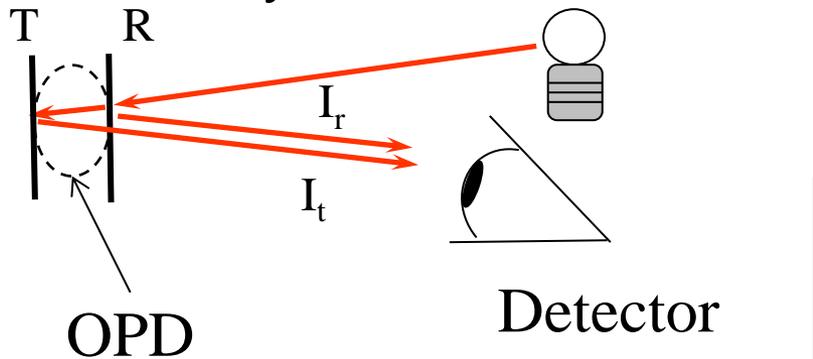
► In the beginning...



Optical Interferometry

- ▶ Measure interference between optical beams traveling two different paths

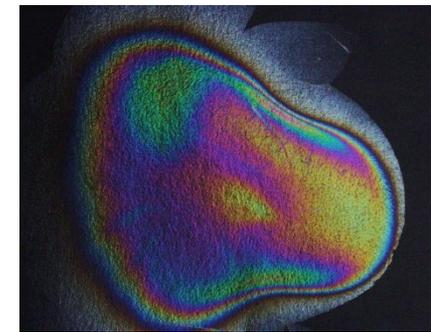
- Fizeau Cavity



Optical path difference

Function of time, position, wavelength...

$$I \sim \text{COS}(2\pi/\lambda * \text{OPD})$$

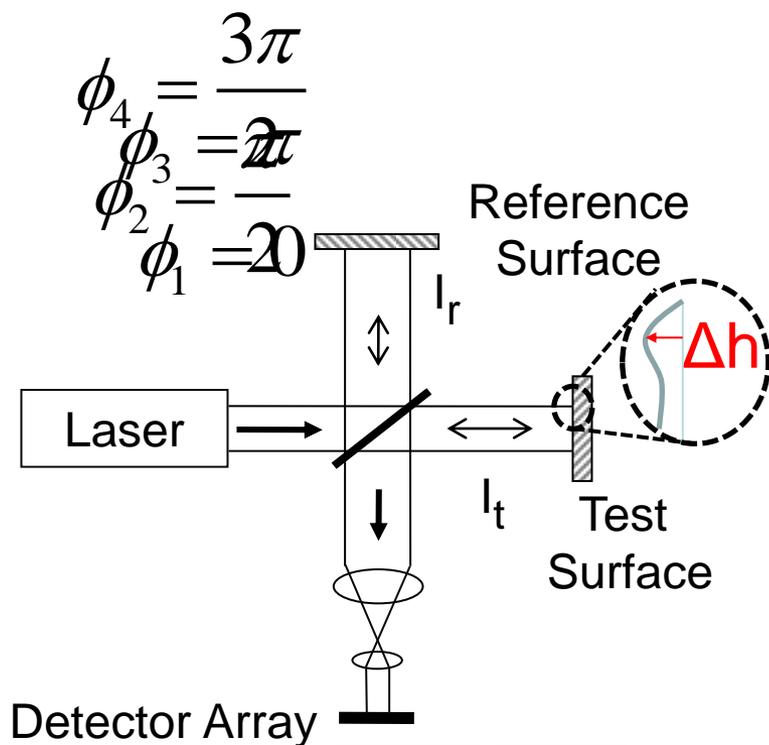


- Thin Film Interference



- White Light Interference in a Bubble

Temporal Phase-Shift Interferometry



$$I_n = I_T(1 + \gamma \cos(\phi + \phi_n))$$

$$\phi = \frac{4\pi \Delta h}{\lambda}$$

$$\gamma = \frac{2 \sqrt{I_t \cdot I_r}}{I_t + I_r}$$



$$I_1 = I_T(1 + \gamma \cos(\phi))$$



$$I_2 = I_T(1 - \gamma \sin(\phi))$$



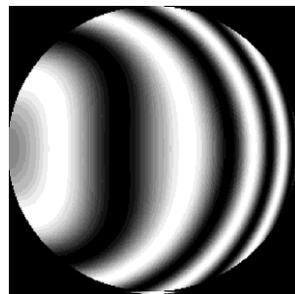
$$I_3 = I_T(1 - \gamma \cos(\phi))$$



$$I_4 = I_T(1 + \gamma \sin(\phi))$$

120 milliseconds for acquisition

$$I_3(x, y)$$

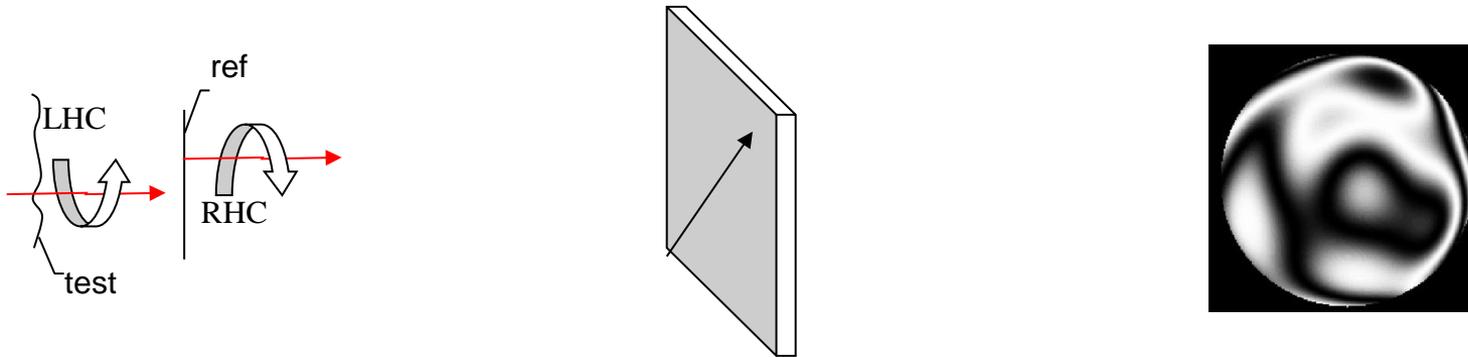


$$\tan(\phi(x, y)) = \frac{I_4(x, y) - I_2(x, y)}{I_3(x, y) - I_1(x, y)}$$

$$\text{Height}(x, y) = \frac{\lambda}{4\pi} \phi(x, y)$$

Polarization Phase Shift Method

Use polarizer as phase shifter



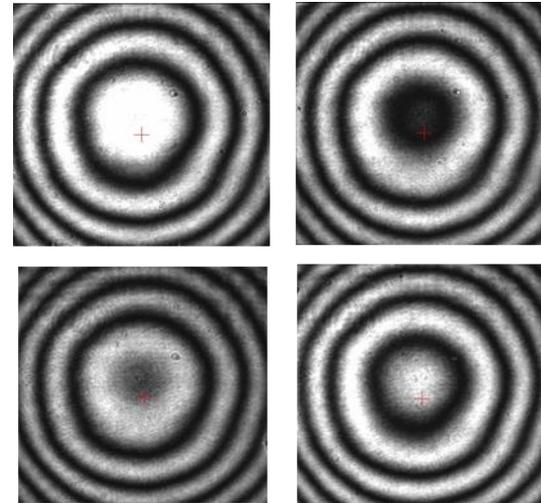
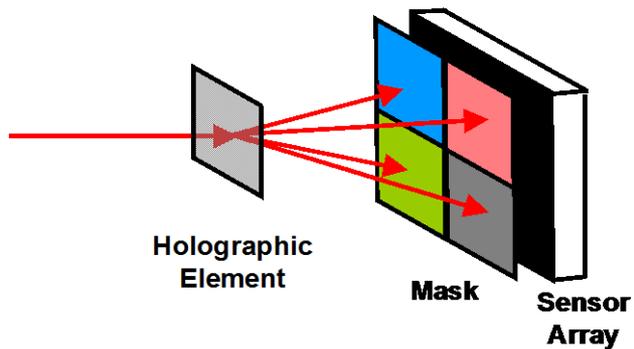
Circular polarized beams (θ) + linear polarizer (α) \Rightarrow $I = I_T(1 + \gamma \cos(\theta + 2\alpha))$

Phase-shift depends on polarizer angle

Kothiyal and Delsile, (1985)

Early Technology

Image division + bulk polarization elements



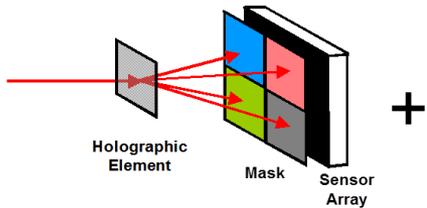
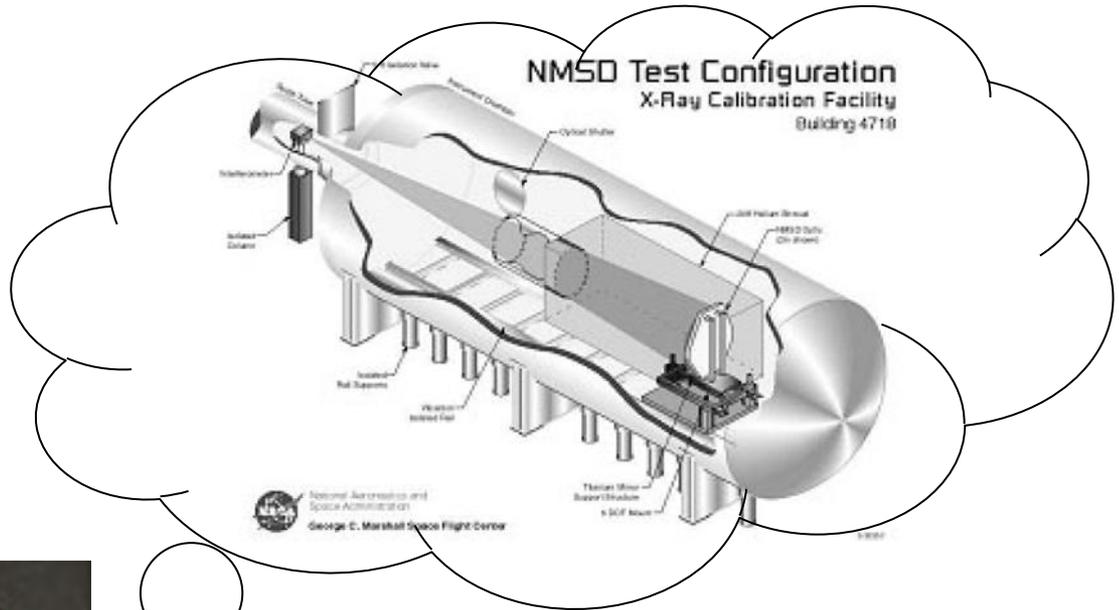
- **Single Frame Acquisition**
- **Simplified Optical Setup**



► The NASA Connection

The NASA Connection

► Then we met Phil...



NASA Related Projects



• **2001**

PhaseCam

Mirror Vibration testing

Modal Analysis

• **2003**

4Mpix + Zoom

Segment cryo-figure

Segment phasing

• **2006**

Multi-wavelength

SpeckleCam

Backplane cryo-stability

• **2004**

FizCam

Short Coherence

Secondary cryo-test

• **2011**

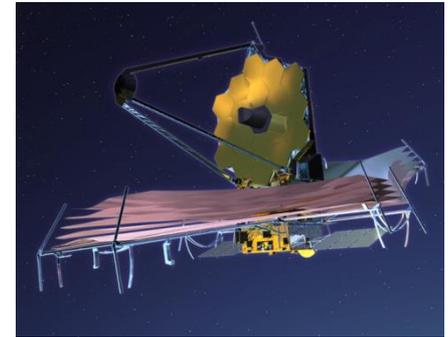
High-speed
1000fps

segment vibration

300mm

Auto-collimating flats

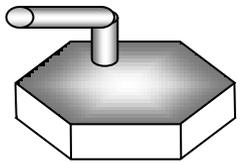
2014



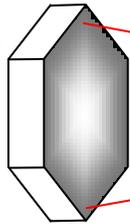
• NASA, ITT, Ball, Tinsley...

Cryo-figuring of mirror segments

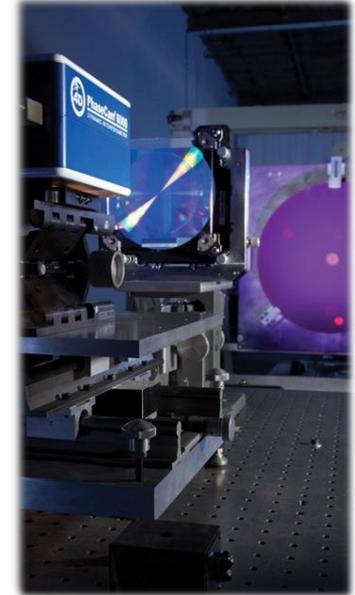
- 1) Polish



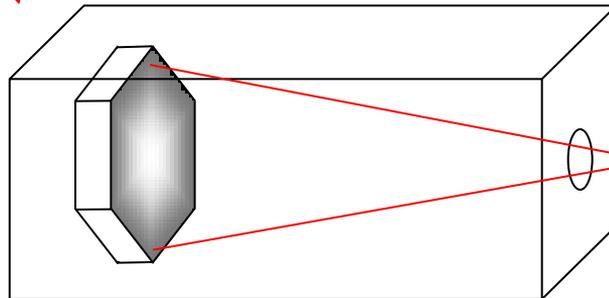
- 2) Measure at ambient



Dynamic Interferometer

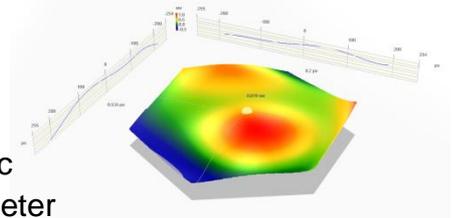


- 3) Measure at cryogenic temp



Dynamic Interferometer

Thermal Chamber

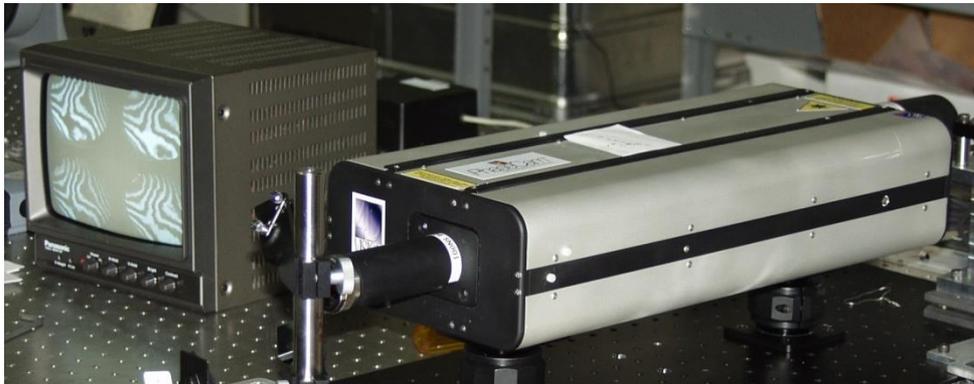


Residual



First application

- NASA Marshall - XRCF



Peak to Valley			RMS		
Uncalibrated Accuracy	Precision	Repeatability	Uncalibrated Accuracy	Precision	Repeatability
<u>.087 wvs</u>	<u>.021 wvs</u>	<u>.0029wvs</u>	<u>.011 wvs</u>	<u>.0024 wvs</u>	<u>.00058 wvs</u>
$\lambda/11.5$	$\lambda/46$	$\lambda/348$	$\lambda/90$	$\lambda/413$	$\lambda/1711$
57 nm	13.8 nm	1.8 nm	7 nm	1.5 nm	0.36 nm

Ball Aerospace – Deep Impact

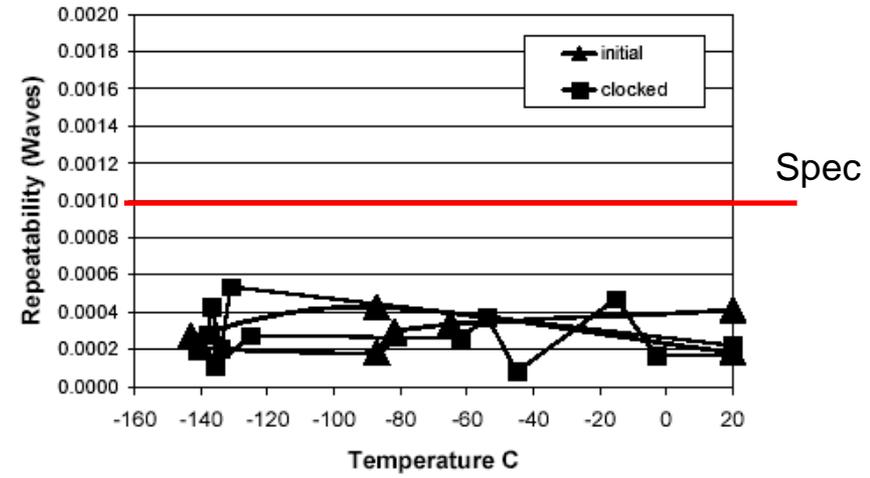
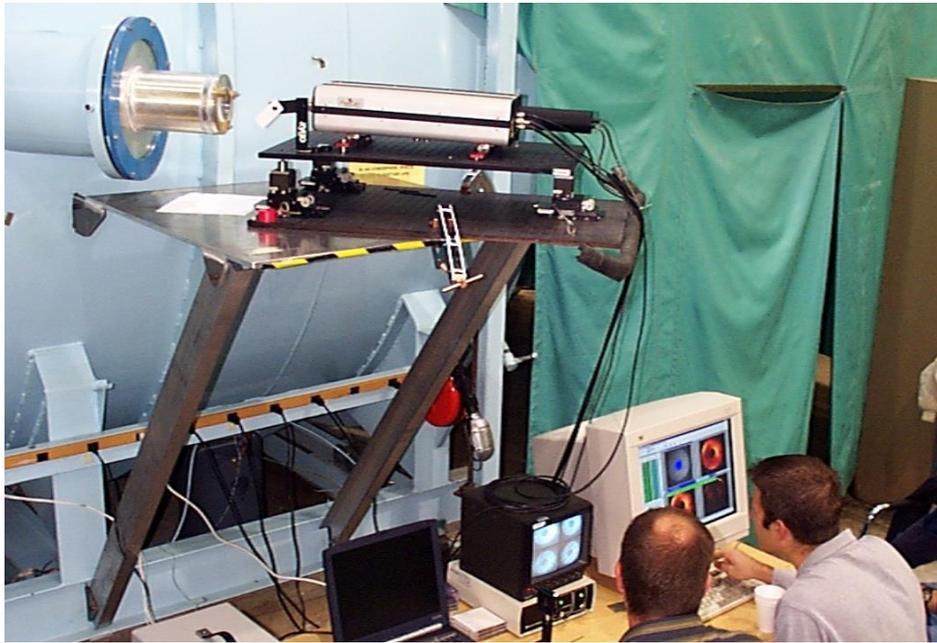
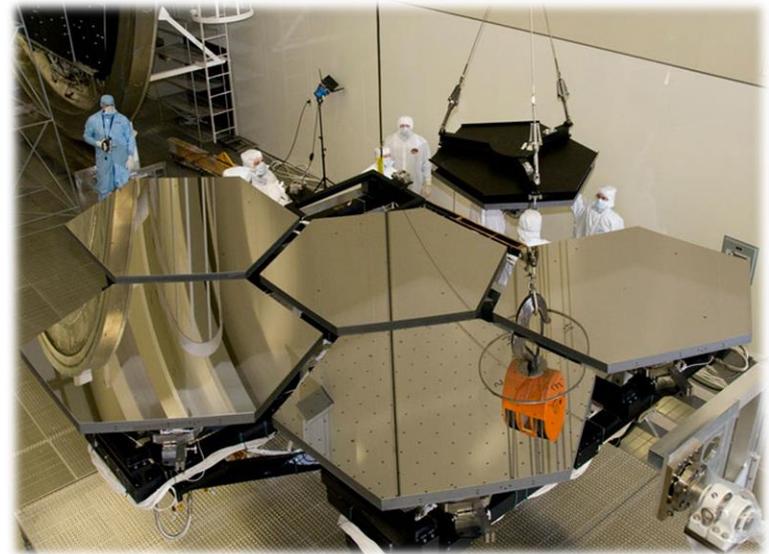
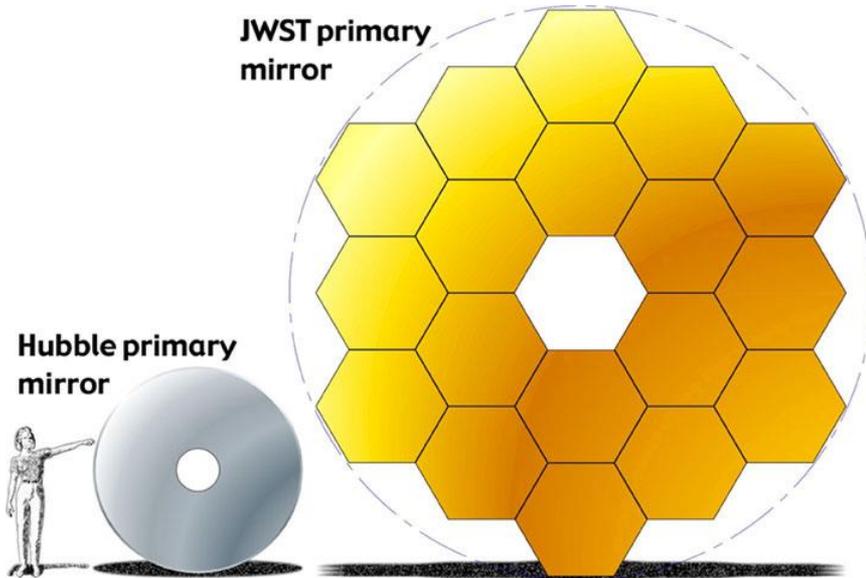
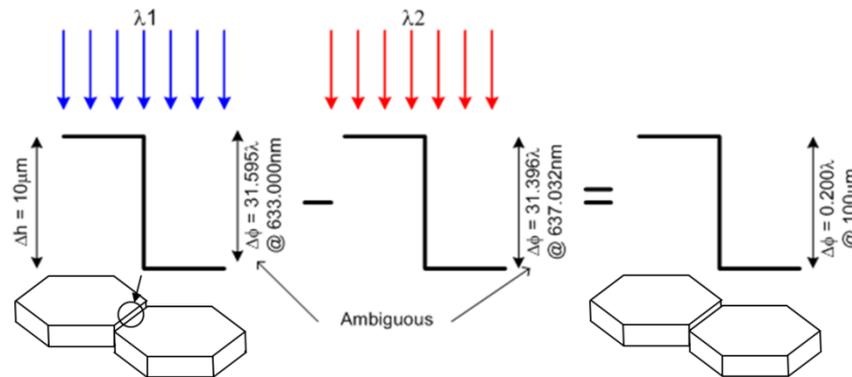


Figure testing of 300 mm Zerodur mirrors at cryogenic temperatures, Baer & Lotz, SPIE 4822-4 July 2002

Mirror Segment Discontinuity



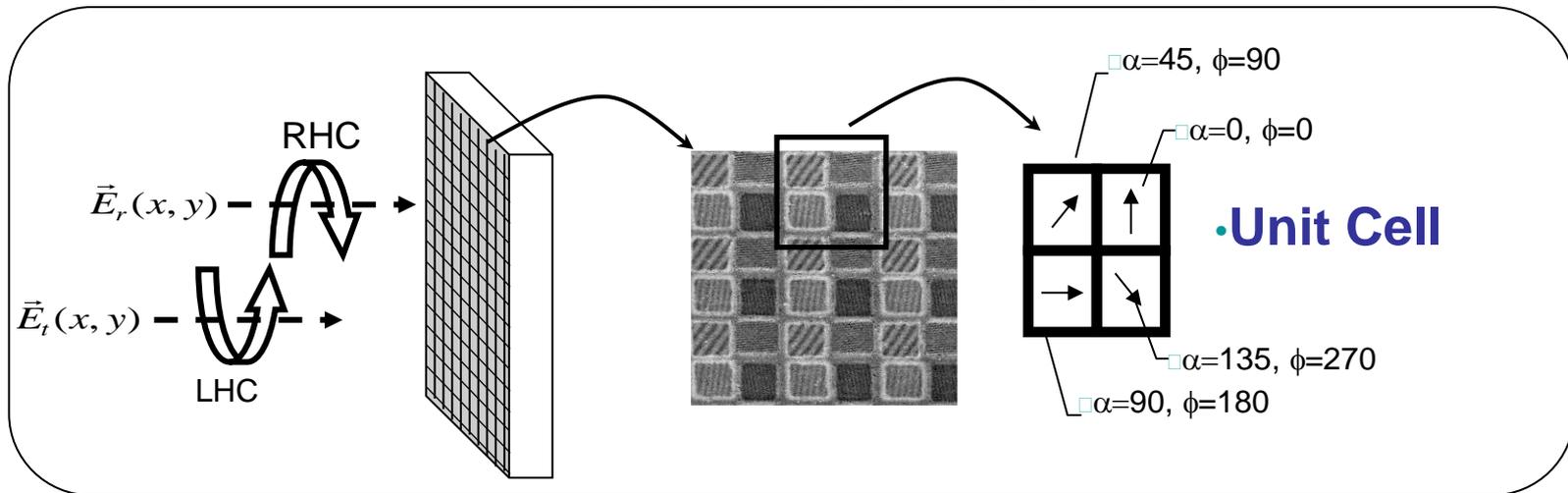
<http://www.jwst.nasa.gov/>



$$\lambda_s = \frac{\lambda_1 \cdot \lambda_2}{|\lambda_2 - \lambda_1|}$$

Dynamic Phase-shift with Micropolarizer Array

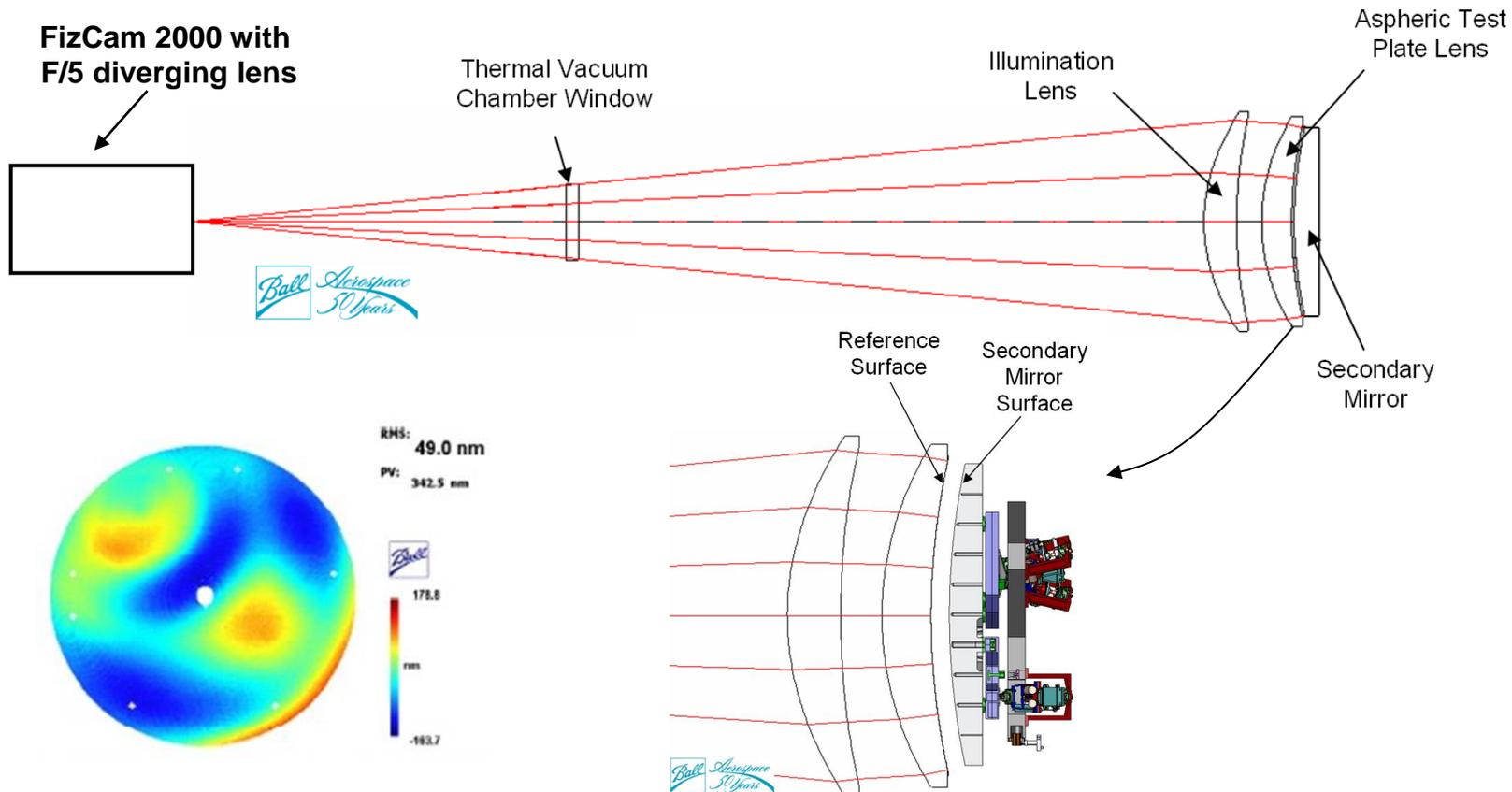
- ▶ Array of oriented micropolarizers
- ▶ Similar to RGB color mask



- ▶ All data is gathered in a single camera frame
- ▶ Allows common path optical arrangement (no tilted beams)
- ▶ Works with broadband source (*multi- λ , or white light*)

Remote Cavity Application

JWST Secondary Mirror Test Configuration
80cm diameter hyperboloid surface

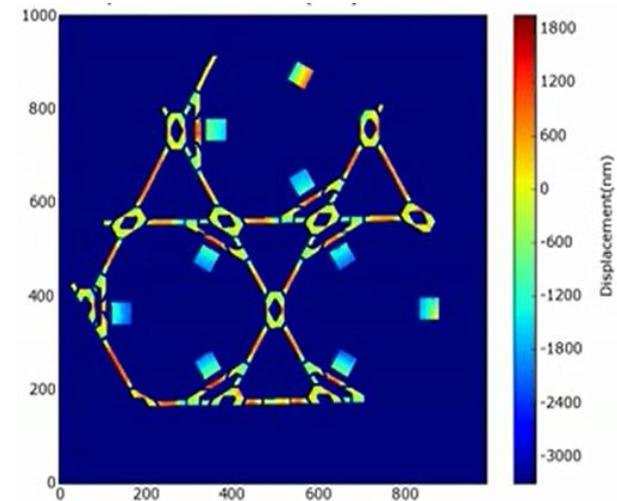


“Cryogenic optical testing results of JWST aspheric test plate lens” Koby Z. Smith, Timothy C. Towell,

Proc. of SPIE Vol. 8126 812600-7

PhaseCam - ESPI

- ▶ Measurement of nm displacement of diffuse objects at 10's meters standoff



- Peter Blake, et. al., "Spatially phase-shifted digital speckle pattern interferometry (SPS-DSPI) and cryogenic structures: recent improvements", Proceedings of SPIE Vol. 7063 2008



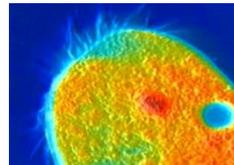
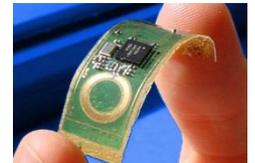
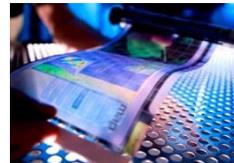
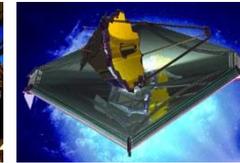
Other Applications and Industries

4D Technology

2014 - 40 employees

4D instruments measure surface, wavefront, and polarization, enabling our customers to:

- **Build next generation optical instruments**
 - Space-based optical systems
 - Large astronomical telescopes
- **Improve manufacturing of industrial and consumer products**
 - Semiconductors, displays, data storage
 - Flexible electronics
- **Increase fundamental understanding**
 - Bio-medical research
 - Astronomy



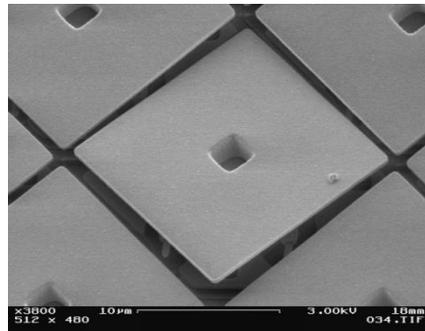
• International Sales, Service and Support



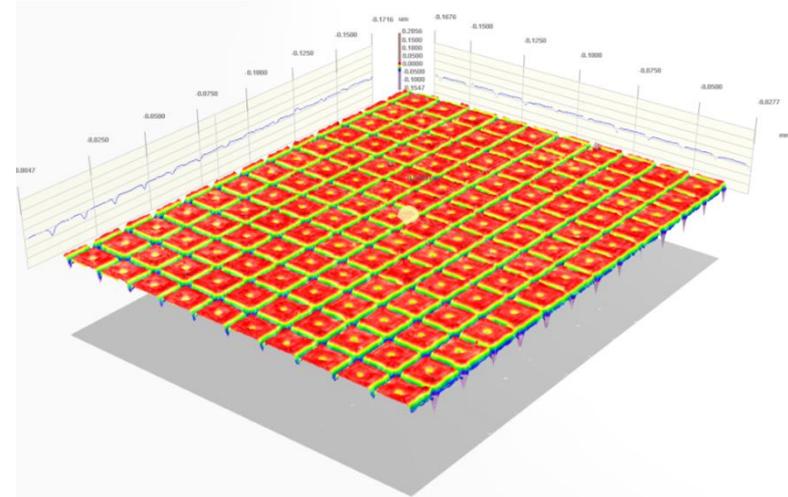
Semiconductor and MEMS



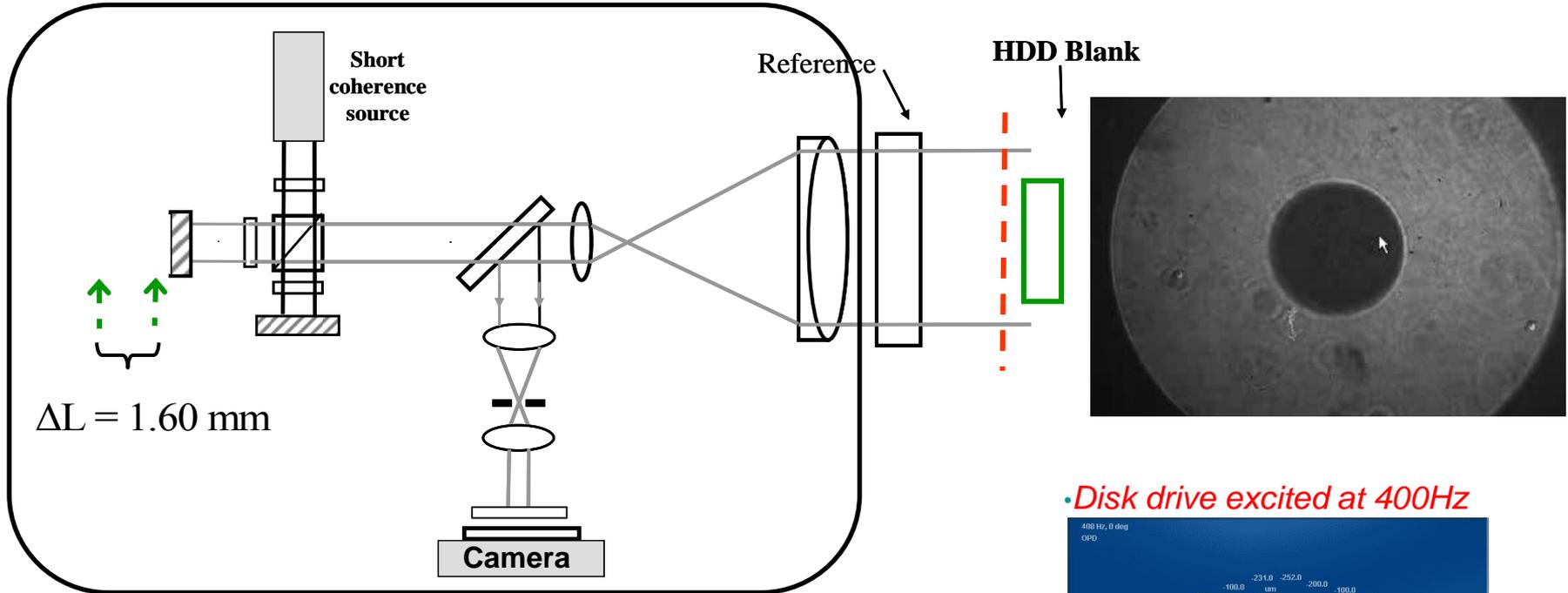
- 193nm
- Photolithography
- Wafer chucks



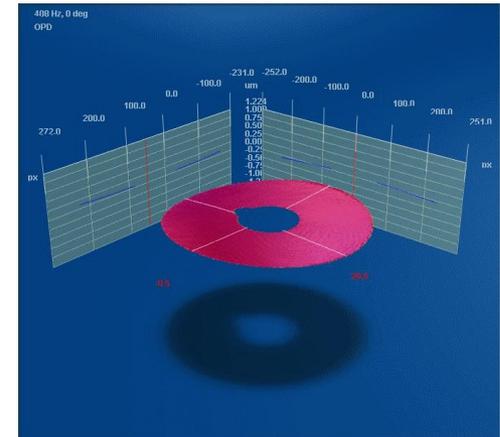
- Digital micro-mirror device



FizCam – Data Storage



• Disk drive excited at 400Hz





NanoCam

▶ NanoCam

- ▶ 3D - Optical surface roughness – critical for large optics
- ▶ Micro-scope based system
- ▶ Dynamic Measurement – operation anywhere

In-situ polishing
process control (On-tool)



Courtesy of Zeeko Ltd

On-optic measurement



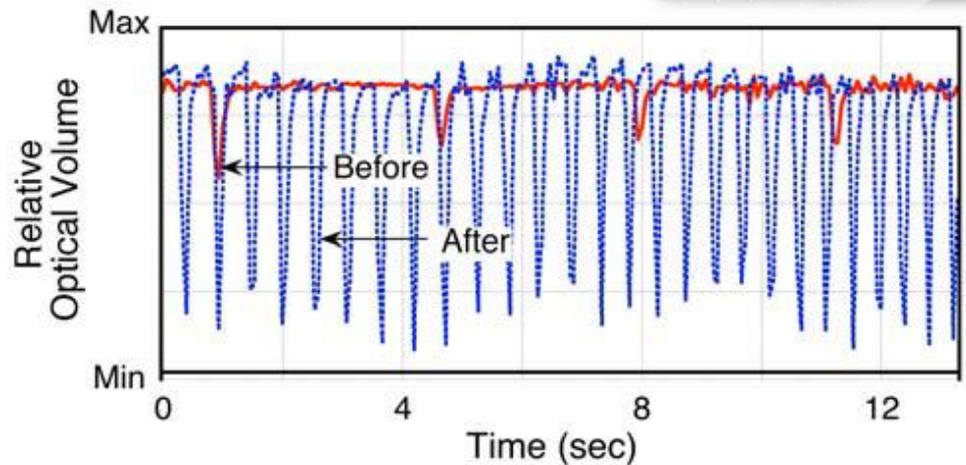
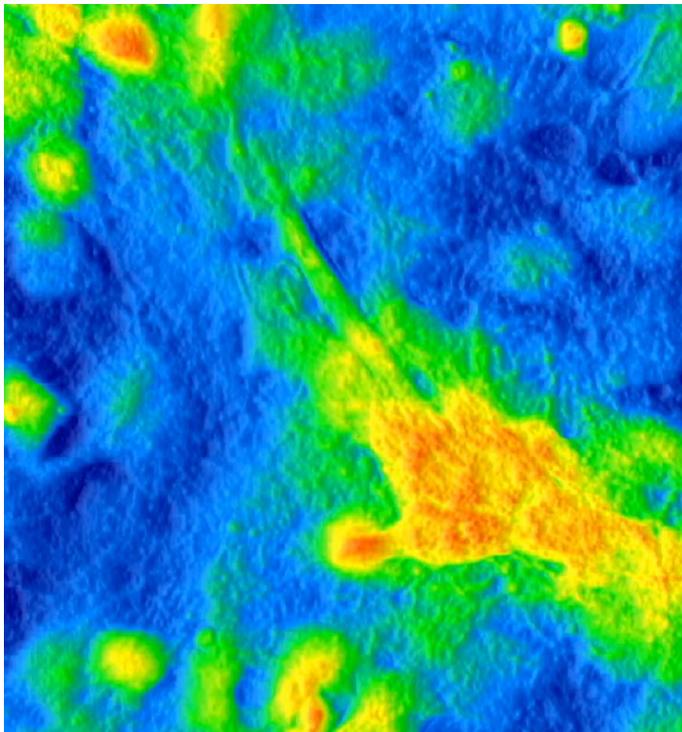
Courtesy Optical Surface Technologies



BioCam

Quantitative Biological Imaging

- Rat cardiac myocytes – before & after medication

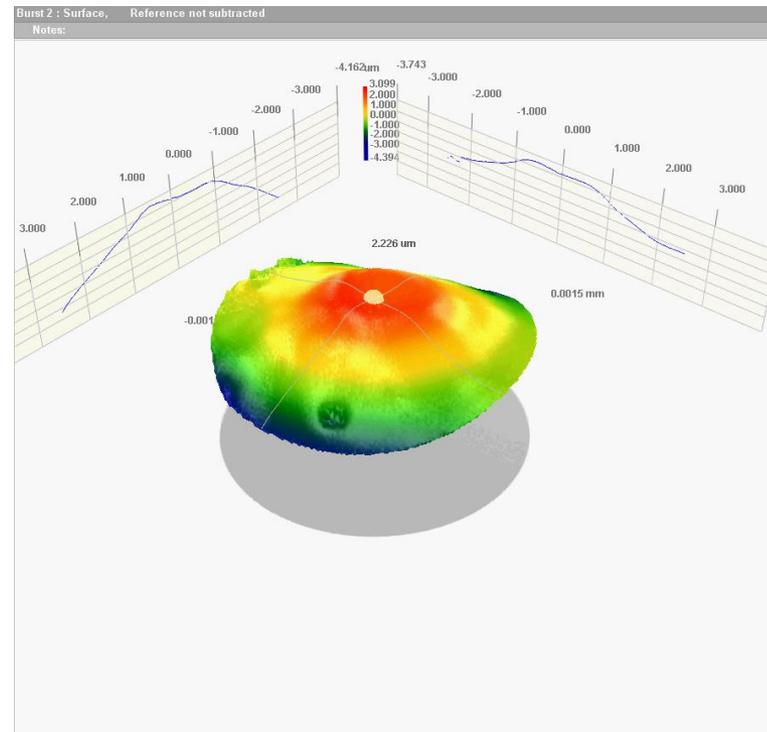
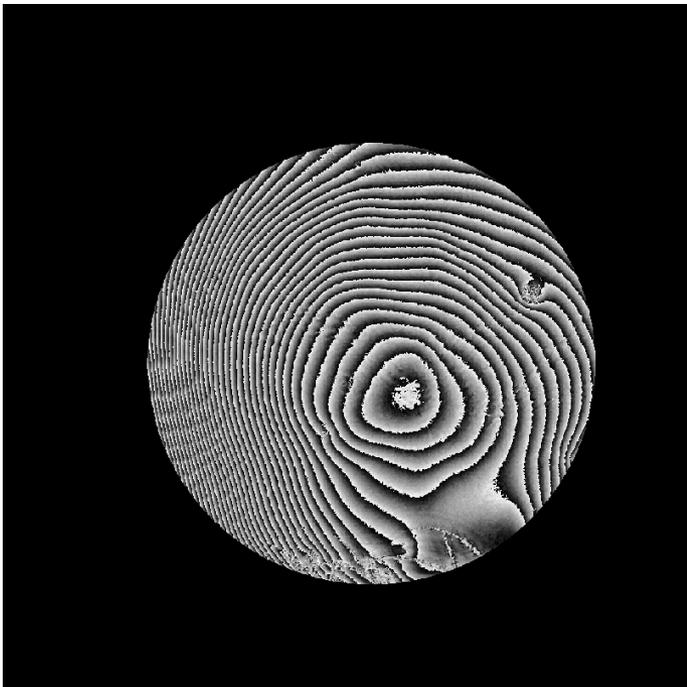


- Both frequency and strength are measured

PhaseCam - Ophthalmic



- Cornea measurement
- Tear film dynamics
- Optics





PolarCam

Micropolarizer Camera

- Enables whole-field, Dynamic polarimetry
 - Wide variety of wavelengths and sensor formats
- Passive illumination
 - Target discrimination, Image enhancement



Rock surface at a depth of 6 feet

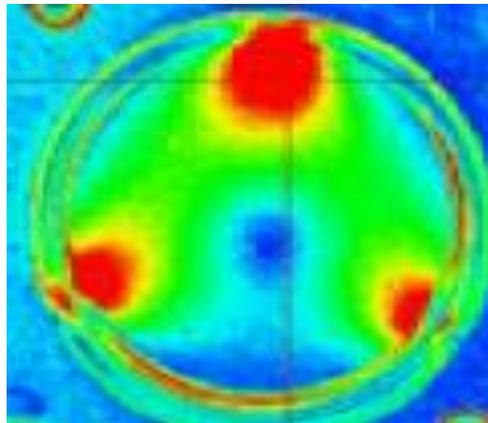


Reference Camera

Enhanced with DoLP

PolarCam – Active Illumination

- ▶ Real-time, quantitative, independent of orientation
- ▶ Product inspection (e.g. containers, packaging, eye wear)
- **25mm diameter window: 0 – 70 nm birefringence**

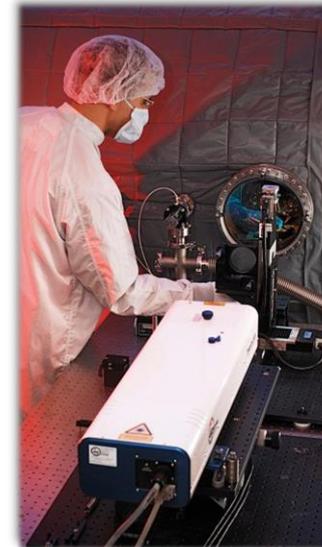




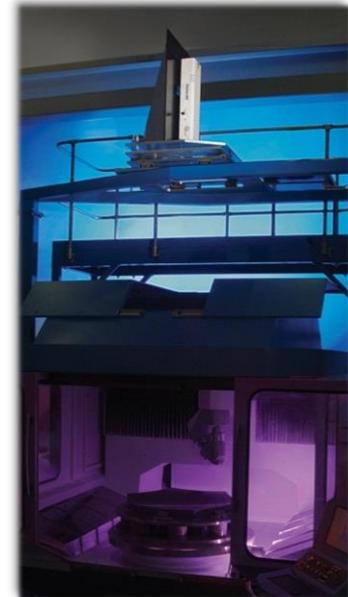
- ▶ NASA sponsored development has lead to:
 - ▶ New Technology
 - ▶ Sustained Job Creation
 - ▶ Better Metrology for Telescopes
 - ▶ Industrial Process Improvement
 - ▶ Fundamental Science



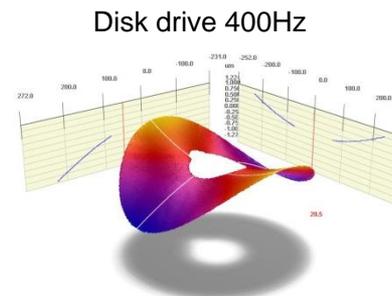
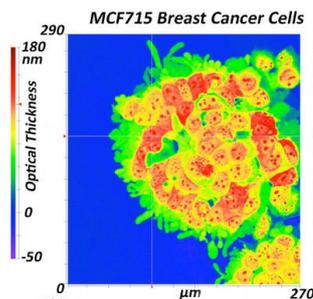
<http://www.jwst.nasa.gov/>



Courtesy of Ball Aerospace



Courtesy of Zeeko Ltd.





Thank you!